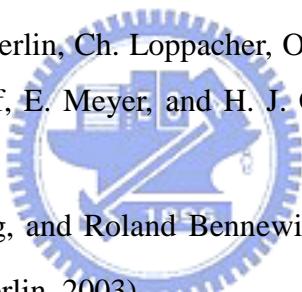


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靜電力對原子力顯微鏡在表面高度量測的影響

Effect of Electrostatic Forces on the Topographic Height Measurement in Frequency
Modulated Atomic Force Microscopy